




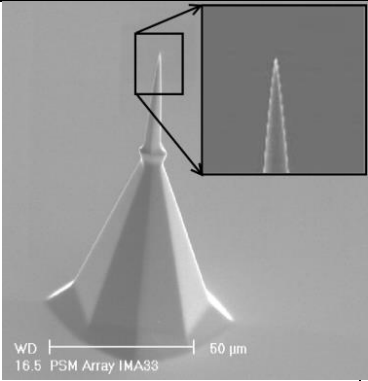
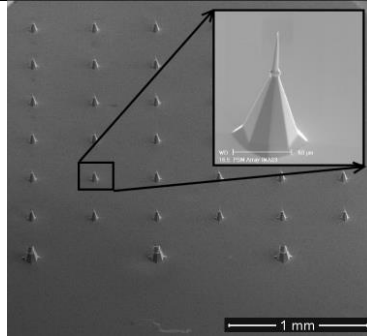
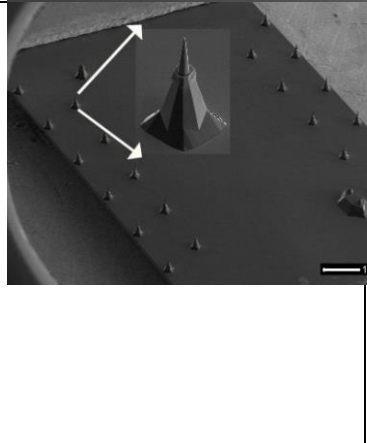
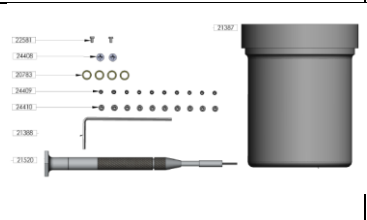

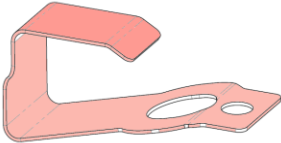
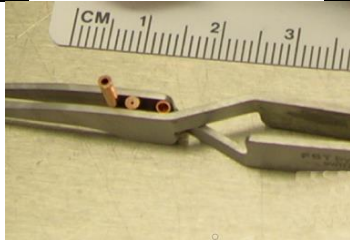
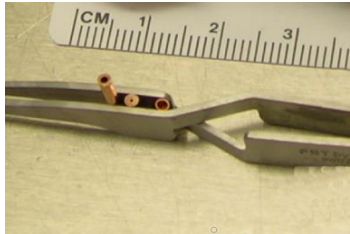
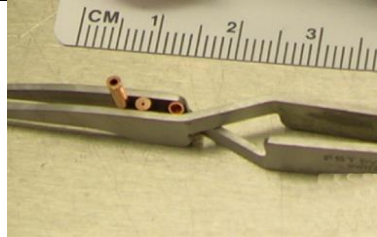
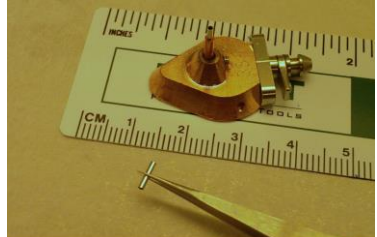







Part Description	Image	Part Number	Lead Time (ARO)
<p>Local Electrode Assembly Si (New) Pre-cleaned, tested and UHV packed. Aperture openings specified between 30 to 60 microns with less than 5 microns variance X to Y (roundness). <i>(Must also order shipment case PN 21400 or supply one.)</i></p>		24603	4 weeks
<p>Local Electrode Si (Refurbished) Refurbished Local Electrodes™ (new cone electrode), pre-cleaned, tested to new specifications and UHV packed. Aperture openings specified between 30 to 60 microns with less than 5 microns variance X to Y (roundness). <i>*Original core electrode pucks must be returned.</i> <i>**If an empty specimen puck is included in the shipment block, a FREE PN 23210 test flat will be included</i></p>		24603-R	4 weeks From receipt of core electrode pucks
<p>Local Electrode Assembly <u>Reflectron Only</u> (New) Pre-cleaned, tested and UHV packed. Openings specified between 30 to 60 microns with less than 5 microns variance. <i>(Must also order shipment case PN 21400 or supply one.)</i></p>		24602	4 weeks
<p>Local Electrode <u>Reflectron Only</u> (Refurbished) Refurbished Local Electrodes™, pre-cleaned, tested to new specifications and UHV packed. Openings specified between 30 to 60 microns with less than 5 microns (roundness). <i>**Original core electrode pucks must be returned.</i> <i>***If an empty specimen puck is included in the shipment block, a FREE PN 23210 test flat will be included.</i></p>		24602-R	4 weeks From receipt of core electrode pucks

Part Description	Image	Part Number	Lead Time (ARO)
LEAP Quality Assurance Test Kit Specimens prepared specifically for testing and QA checks of the LEAP [®] instrument, 10 aluminum specimens, one presharpener microtip coupon, and one local electrode test flat. Includes Specimen Shipping Assembly (PN 21385).		21772	2 weeks
Consumables Credit Package: Provides a credit redeemable against future consumable requirements (supplied at list price up to a maximum value of \$25,000).	Ask your local sales representative for details.	23886	Ask your local sales person for details.
Presharpened Microtip™ Coupons (PSM M36) 36-specimen grid of presharpener microtips (tapering to a sharp point less than 50nm in diameter); height 100 micron ± 20 micron on a 3mm X 7mm (±0.2mm) silicon coupon doped to less than 0.1 Ohm-cm resistivity. Shipped in packages of 10 coupons, requires mounting to planar sample stub (not included). Guaranteed > 80% of the tips are viable on shipment.		21611	2 weeks
Presharpened Microtip Coupon As above. Shipped as quantity of 1 or more coupons.		21505	2 weeks

Part Description	Image	Part Number	Lead Time (ARO)
<p>Microtip for FIB Liftout Mounting (FT M36 - LEAP 3000) 36-specimen grid of flat top microtips with diameter $2\ \mu\text{m} \pm 1\ \mu\text{m}$; height 110 micron ± 20 micron on a 3mm X 7mm ($\pm 0.2\text{mm}$) silicon coupon doped to $< 0.1\ \text{Ohm-cm}$ resistivity. Shipped in packages of 10 coupons, requires mounting to planar sample stub (not included). Guaranteed $> 80\%$ of the tips are viable on shipment.</p>		21909	2 weeks
<p>Microtip for FIB Liftout Mounting (LEAP 3000) Shipped as quantity of 1 or more coupons</p>		21753	2 weeks
<p>Microtip Coupons for FIB Liftout (M22) 22-specimen grid of flat top microtips with a tips located within 400 microns of the edge of the microtip coupon. Diameter $2\ \mu\text{m} \pm 1\ \mu\text{m}$; height 125 micron ± 20 micron on a 3mm X 7mm ($\pm 0.3\text{mm}$ - thicker) silicon coupon doped $< 0.1\ \text{Ohm-cm}$ resistivity. Shipped in packages of 10 coupons, requires mounting to planar sample stub (not included PN 23739). Guaranteed $> 80\%$ of the tips are viable on shipment.</p>		23265	2 weeks
<p>Microtip Coupon for FIB Liftout (M22) As above. Shipped as quantity of one or more coupons</p>		23264	2 weeks
<p>Spare Parts Kit Contains screws, set screws, and washers for pucks, screws for microtip spring clips, and a replacement cover and base for the 18 position sample holder. Also includes Allen keys for tightening specimen puck set screws and specimen storage set screws.</p>		24407	2 weeks

Part Description	Image	Part Number	Lead Time (ARO)
ARM™ replacement needles Pre-bent replacements for the rotation needle on ARM stages. (PN 23213). Comes as a package of two.		23917	2 weeks
Cu Spring Clip Replacement Replacement clips for spring clip microtip stubs PN 23739. Comes as a package of 5.		24501	2 weeks
Small ID Sample Stub s (copper crimps) Pre-cleaned and UHV packaged in quantities of 100 each. General use stubs for wire samples. Inside diameter 0.4mm. OD 1.8mm. 8mm length.		21609	2 weeks
Medium ID Sample Stubs (copper crimps) - LONG Pre-cleaned and UHV packaged in quantities of 25 each. Precision inside diameter measures 1.0mm – accepts 3DAP Ni crimps (see PN 23863). OD 1.8mm. 14mm length. Also available with an 8mm length, packet of 25. - SHORT		22933 24508	2 weeks TBD

Part Description	Image	Part Number	Lead Time (ARO)
<p>Large ID Sample Stub (copper crimps) Pre-cleaned and UHV packaged in quantities of 100 each. Inside diameter measures 1.4mm. OD 1.8mm. 8mm length.</p>		21610	2 weeks
<p>3DAP Sample Stub (Ni crimps) Precision Ni crimp for use in a 3DAP™ systems. Fits inside Medium ID Sample Stubs PN 22933. Pre-cleaned and UHV packaged in quantities of 25 each. OD 1.00 mm, ID 0.8mm. 5mm length.</p>		23863	4 weeks
<p>Planar Sample Stubs Pre-cleaned and UHV packaged in quantities of 25 stubs each. Diameter: 0.25" (6.35 mm) Height: 0.48" (12.2mm)</p>		21600	2 weeks
<p>Specimen, Test, Aluminum Single aluminum specimen prepared specifically for testing and calibrating the LEAP instrument. <i>(Must also order container PN 21385.)</i></p>		21634	2 weeks

Part Description	Image	Part Number	Lead Time (ARO)
Specimen, Test, Stainless-Steel Single stainless-Steel specimen prepared specifically for testing and calibrating the LEAP instrument. <i>(Must also order container PN 21385.)</i>	See PN 21634	21635	2 weeks
Specimen, Test, Tungsten Single tungsten specimen prepared specifically for testing and calibrating the LEAP instrument. <i>(Must also order container PN 21385.)</i>	See PN 21634	21636	2 weeks
Silver Epoxy Kit Conductive epoxy (Silver embedded) for mounting specimens to stubs – especially for mounting microtip coupon samples to planar stubs without the use of a spring clip. Price and availability subject to change.		21614	8 weeks
FIM Gas Bottle Refill You must obtain an RMA number before shipping the bottles back to us. **Contact Service for installation quotation.		21009-R	4 weeks after receipt of bottle –installation not included
Bulb, Replacement Replacement halogen lamp for LEAP [®] 3000 specimen transfer and alignment lighting system.		21449	2 weeks

Part Description	Image	Part Number	Lead Time (ARO)
<p><u>Accessories Packages:</u></p> <p>1st Year Metallurgical Package: Provides a comprehensive package of consumables and accessories to supply a typical group concentrating on metallurgical sample analysis for approximately 1 year.</p> <p>1st Year FIB-Based Package: Provides a comprehensive package of consumables and accessories to supply a typical group concentrating on FIB-based sample analysis for approximately 1 year.</p>		<p>23809</p> <p>23858</p>	<p>Ask your local sales person for details.</p>